

Notice of References Cited	Application/Control No. 10/734,870		Applicant(s)/Patent Under Reexamination LEEK ET AL.	
	Examiner Jeanette E. Chapman		Art Unit 3633	Page 1 of 1

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*	B	US-3,172,509	03-1965	DUGGER RALPH L	49/501
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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